## Notice of References Cited Application/Control No. 10/617,524 Examiner Shew-Fen Lin Applicant(s)/Patent Under Reexamination FELLENSTEIN ET AL. Art Unit Page 1 of 1

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2002/0188612 A1	12-2002	Yu et al.	707/100
*	В	US-2003/0046270 A1	03-2003	Leung et al.	707/1
*	С	US-6,564,214 B1	05-2003	Bhide, Chandrashekhar	707/6
*	D	US-2003/0182274 A1	09-2003	Oh, Young-June	707/3
*	Е	US-2004/0158676 A1	08-2004	Kasmirsky et al.	711/117
*	F	US-6,772,143 B2	08-2004	Hung, Yat-Sang	707/3
*	G	US-2004/0172419 A1	09-2004	Morris et al.	707/200
*	Н	US-2004/0214554 A1	10-2004	Binning et al.	455/414.1
	1	US-			
	J	US-			
	К	US-			:
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q					
	R					
	S					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)	
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	w		
	х		

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.